

IGBT³ Chip

FEATURES:

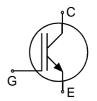
- 600V Trench & Field Stop technology
- $\begin{array}{ll} \text{low} \ \ V_{\text{CE(sat)}} \\ \text{low turn-off losses} \end{array}$
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

power module

Applications:

• drives



Chip Type	V _{CE}	<i>I</i> _C	Die Size	Package
SIGC40T60R3E	600V	75A	5.74 x 6.96 mm ²	sawn on foil

Mechanical Parameters

Raster size	5.74 x 6.96		
Emitter pad size (incl. gate pad)	(2.356 x 2.907) x 4	2	
Gate pad size	1.615 x 0.817	mm ²	
Area total	40		
Thickness	70	μm	
Wafer size	200	mm	
Max.possible chips per wafer	657		
Passivation frontside	Photoimide		
Pad metal	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	Electrically conductive glue or solder		
Wire bond	Al, <500μm		
Reject ink dot size	Ø 0.65mm; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, T_{vj} =25 °C	V _{CE}	600	V	
DC collector current, limited by $T_{\rm vj\;max}$	I _C	1)	Α	
Pulsed collector current, t_p limited by $T_{vj max}$	I _{c,puls}	225	Α	
Gate emitter voltage	V _{GE}	±20	V	
Junction temperature range	T_{vj}	-40 +175	C	
Operating junction temperature	T_{vj}	-40+150	°C	
Short circuit data 2 $V_{\rm GE}$ = 15V, $V_{\rm CC}$ = 360V, $T_{\rm vj}$ = 150°C	t_{SC}	6	μs	
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{C,max} = 150A, V_{CE,max} = 600V$ $T_{vj} \le 150 ^{\circ}C$			

¹⁾ depending on thermal properties of assembly

Static Characteristics (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter	Oymboi	Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 4 mA	600			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =75A	1.05	1.45	1.85	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =1.2 mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V_{CE} =600V , V_{GE} =0V			3.8	μA
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			600	nA
Integrated gate resistor	$r_{\rm G}$			4		Ω

Dynamic Characteristics (not subject to production test - verified by design / characterization),

*T*_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
raiametei	Syllibol	Conditions	min.	typ.	max.	Oilit
Input capacitance	Cies	$V_{CE}=25V$,		4700		
Output capacitance	Coes	$V_{GE}=0V$,		300		pF
Reverse transfer capacitance	C _{res}	f=1MHz		145		

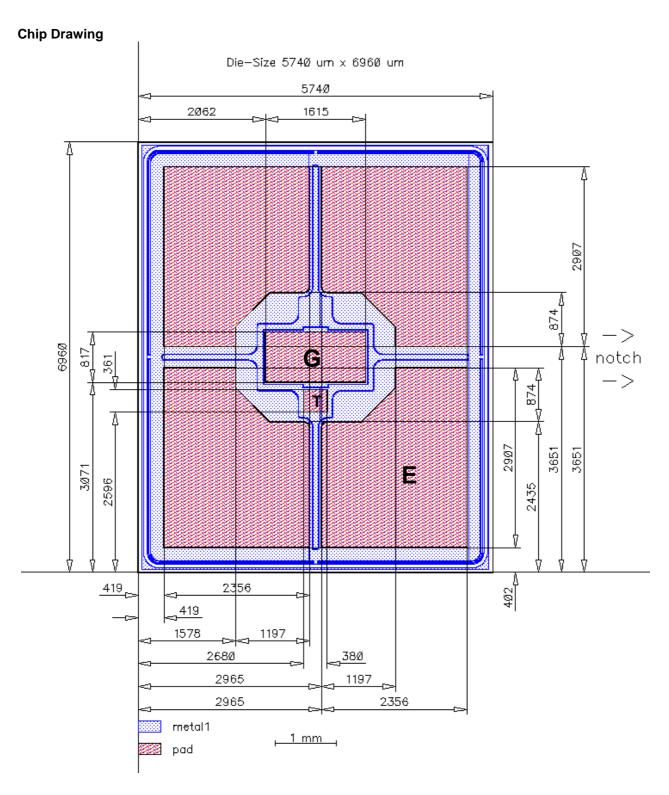
²⁾ not subject to production test - verified by design/characterization



Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.





E = Emitter

G = Gate

T = Test pad do not contact



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date
2.2	Wafer diameter change to 200 mm	06.07.2010

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